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Form PTO-1449 (Substitute) Information Disclosure Statement BY APPLICANT (Use several sheets if necessary)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Attorney Docket Number LAZE-01015US1	Serial/Patent Number 10/684,760
	Applicant/Patent Owner Thomas F. Rust		
	Filing/Issue Date October 14, 2003	Group Art Unit 3681 3708	

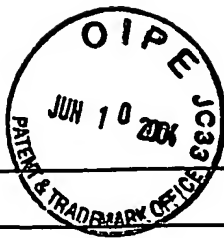
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<i>U</i>	2	4,575,822	03/11/86	Quate	365	174	02/15/83
	3	4,829,507	05/09/89	Kazan et al.	369	126	08/15/88
	4	4,831,614	05/16/89	Duerig et al.	369	101	03/13/87
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	6	4,945,515	07/31/90	Ooumi et al.	365	174	09/12/88
	7	4,962,480	10/09/90	Ooumi et al.	365	151	09/12/88
	8	4,987,312	01/22/91	Eigler	250	492.3	11/07/89
	9	5,038,322	08/06/91	Van Loenen	365	114	02/03/89
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<i>pm</i>	21	5,265,046	11/23/93	Fuchs et al.	365	151	12/30/91
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<i>[Signature]</i>	60	JP3295043	12/26/91	JAPAN	<i>[Signature]</i>	<i>[Signature]</i>	X	
<i>[Signature]</i>	61	JP3295044	12/26/91	JAPAN	<i>[Signature]</i>	<i>[Signature]</i>	X	
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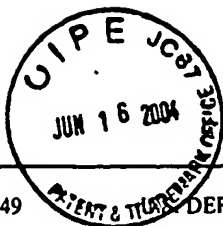


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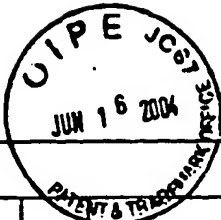
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